Next-Generation Fault Detection Offers Full Trace Analysis Overcoming the Limitations of Legacy FDC Systems

To realize the full potential of smart manufacturing, customers can no longer afford to count on legacy FDC systems alone for accurate fault detection. Traditional FDC relies solely on summary trace data from sensors for fault detection. As a result, small changes in sensor behavior can go undetected, resulting in a potentially catastrophic impact on yield. In addition, modeling FDC systems is a highly time-consuming proposition. BISTel's new Dynamic Fault Detection (DFD) system overcomes these challenges by offering full trace data coverage and increases productivity by eliminating the need for timely and costly modeling. DFD is a bridge to smart factory manufacturing because it can also integrate seamlessly to legacy FDC systems.

Accurate Fault Detection

Sensor trace data contains a wealth of information that helps manufacturers quickly identify potential yield

- Real-time monitoring improves product quality and yield
- The elimination of SPC modeling